MSE-636(b) Scanning electron microscopy techniques (b)

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Cursus	Sem.	Туре	Language of	Englis
Materials Science and Engineering		Obl.	teaching	Linglis
			Credits	1
			Session	
			Exam	Writter
			Workload	30h
			Hours	15
			Courses	12
			TP	3
			Number of positions	26

Frequency

Every year

Remark

Online course

Summary

This intensive course is intended for researchers who envisage to use scanning electron microscopy techniques for their research or who want to understand how to interpret SEM images and analytical results presented in scientific publications.

Content

This intensive course is intended for researchers who are potential new users of scanning electron microscopes. It will provide them with a basic understanding of the instruments, optics of SEM, the imaging modes, the associated analytical techniques EDS and EBSD, related theories of image formation.

Demonstrations will be given on the microscopes.

2x Year Spring (b) and autumn (a)

Keywords SEM, FIB, ESEM

Assessment methods Written